Patent Overlay Maps: Spain and the Basque Country

Javier Gavilanes-Trapote, Gaizka Garechana, Rosa María Rio-Belver, Ernesto Cilleruelo, Jaso Larruscain-Sarasola

University of the Basque Country
E mail: javier.gavilanes@ehu.es

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Abstract

This study uses the new global patent map developed by Rafols et al. (2012) to reflect the patenting activity of Spain together with the activity of the Basque Country, a highly industrialized region in Spain, for the time interval 2000-2006. The global patent map reflects the technological categories where a patent could be categorized according to the International Patent Classification (IPC) system, together with the degree of similarity among different IPC's, deter-mined using the citing-to-cited relationships as bonds between categories. An overlay method has been developed to locate patent data of individual organiza-tions/regions/countries and technological fields in a visual and comprehensive way in this global map. A first overlay has been conducted using data correspond-ing to Spanish patenting activity, collected from PATSAT database of European Patent Office (EPO) by using the nationality of applicants as selection criteria. The second overlay, corresponding to the Spanish region of the Basque Country, has required access to the INVENES database of Spanish Patent and Trademark Office (OEPM) in order to determine the region corresponding to each Spanish patent.